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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
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10/701,332

11/04/2003

Ghasi R. Agrawal

03-1343

5874

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7590

10/26/2009

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EXAMINER

NGUYEN, STEVE N

ART UNIT

PAPER NUMBER

2117

MAIL DATE

DELIVERY MODE

10/26/2009

PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

Office Action Summary	Application No. 10/701,332	Applicant(s) AGRAWAL ET AL.	
	Examiner STEVE NGUYEN	Art Unit 2117	

-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address --

Period for Reply

A SHORTENED STATUTORY PERIOD FOR REPLY IS SET TO EXPIRE 3 MONTH(S) OR THIRTY (30) DAYS, WHICHEVER IS LONGER, FROM THE MAILING DATE OF THIS COMMUNICATION.

- Extensions of time may be available under the provisions of 37 CFR 1.136(a). In no event, however, may a reply be timely filed after SIX (6) MONTHS from the mailing date of this communication.
- If NO period for reply is specified above, the maximum statutory period will apply and will expire SIX (6) MONTHS from the mailing date of this communication.
- Failure to reply within the set or extended period for reply will, by statute, cause the application to become ABANDONED (35 U.S.C. § 133). Any reply received by the Office later than three months after the mailing date of this communication, even if timely filed, may reduce any earned patent term adjustment. See 37 CFR 1.704(b).

Status

- 1) ☒ Responsive to communication(s) filed on 14 July 2009.
- 2a) ☒ This action is **FINAL**. 2b) ☐ This action is non-final.
- 3) ☐ Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under *Ex parte Quayle*, 1935 C.D. 11, 453 O.G. 213.

Disposition of Claims

- 4) ☒ Claim(s) 15-26 is/are pending in the application.
- 4a) Of the above claim(s) _____ is/are withdrawn from consideration.
- 5) ☐ Claim(s) _____ is/are allowed.
- 6) ☒ Claim(s) 15-26 is/are rejected.
- 7) ☐ Claim(s) _____ is/are objected to.
- 8) ☐ Claim(s) _____ are subject to restriction and/or election requirement.

Application Papers

- 9) ☐ The specification is objected to by the Examiner.
- 10) ☒ The drawing(s) filed on 10 August 2006 is/are: a) ☒ accepted or b) ☐ objected to by the Examiner.
Applicant may not request that any objection to the drawing(s) be held in abeyance. See 37 CFR 1.85(a).
Replacement drawing sheet(s) including the correction is required if the drawing(s) is objected to. See 37 CFR 1.121(d).
- 11) ☐ The oath or declaration is objected to by the Examiner. Note the attached Office Action or form PTO-152.

Priority under 35 U.S.C. § 119

- 12) ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some * c) ☐ None of:
- ☐ Certified copies of the priority documents have been received.
 - ☐ Certified copies of the priority documents have been received in Application No. _____.
 - ☐ Copies of the certified copies of the priority documents have been received in this National Stage application from the International Bureau (PCT Rule 17.2(a)).

* See the attached detailed Office action for a list of the certified copies not received.

Attachment(s)

- | | |
|--|---|
| 1) <input checked="" type="checkbox"/> Notice of References Cited (PTO-892) | 4) <input type="checkbox"/> Interview Summary (PTO-413) |
| 2) <input type="checkbox"/> Notice of Draftsperson's Patent Drawing Review (PTO-948) | Paper No(s)/Mail Date. _____ |
| 3) <input type="checkbox"/> Information Disclosure Statement(s) (PTO/SB/08) | 5) <input type="checkbox"/> Notice of Informal Patent Application |
| Paper No(s)/Mail Date _____ | 6) <input type="checkbox"/> Other: _____ |

DETAILED ACTION

Claims 15-26 are currently pending.

Response to Arguments

Applicant's arguments with respect to claims 15-26 have been considered but are moot in view of the new ground(s) of rejection.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negated by the manner in which the invention was made.

The factual inquiries set forth in *Graham v. John Deere Co.*, 383 U.S. 1, 148 USPQ 459 (1966), that are applied for establishing a background for determining obviousness under 35 U.S.C. 103(a) are summarized as follows:

1. Determining the scope and contents of the prior art.
2. Ascertaining the differences between the prior art and the claims at issue.
3. Resolving the level of ordinary skill in the pertinent art.
4. Considering objective evidence present in the application indicating obviousness or nonobviousness.

Claims 15, 16, 21, and 22 rejected under 35 U.S.C. 103(a) as being unpatentable over Frankowsky (US Pat. 6,961,880) in view of Miller et al (US Pat. Pub.

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2003/0237061; hereinafter referred to as Miller) in view of Shih et al (US Pat. 6,661,719; hereinafter referred to as Shih).

As per claims 15 and 21:

Frankowsky teaches a method for testing memory, said method comprising:

- performing a first test, wherein functional memory is tested (Fig. 2, 22; col. 2, lines 49-51);
- repairing the functional memory by adding access to redundant elements, thereby providing repaired functional memory (Fig. 2, 24; col. 2, lines 51-52);
- after repairing the functional memory, adding access to redundant memory not required for the repair of the functional memory (col. 2, line 63 to col. 3, line 1; the unused redundant memory is accessed and tested in step 28 of Fig. 2 which occurs after steps 22 and 24); and
- performing a third test, wherein redundant memory is tested (col. 2, lines 59-63).

Not explicitly disclosed by Frankowsky is performing a second test, wherein the repaired functional memory is tested. However, Miller in an analogous art teaches re-testing the functional memory which has been repaired (Fig. 1; 16). Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to re-testing the functional memory which has been repaired. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that doing so would have ensured that the repair was effective (Miller; paragraph 5).

Not explicitly disclosed by Frankowsky or Miller is after testing the repaired functional memory and then adding access to redundant memory not required for repair of the functional memory, performing a third test, wherein redundant memory is tested. However, Shih in an analogous art teaches repeating burn-in testing of redundant memory (Fig. 3; 160). Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to repeat the burn-in step 28 in Frankowsky after the repair step 30. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that repeating the burn-in sequence would have forced each memory cell to switch with the burn-in level many times further exposing faulty memory arrays (col. 5, lines 12-15).

As per claims 20 and 26:

Frankowsky further teaches wherein the step of adding access to redundant memory not required for repair of the functional memory comprises adding access to all remaining redundant memory, and wherein the step of performing a third test comprises testing all the remaining redundant memory (col. 2, line 65 to col. 3, line 1; Frankowsky teaches accessing and testing all unused redundant elements).

As per claims 16 and 22:

Frankowsky further teaches using repair information to repair the functional memory (col. 2, lines 51-54).

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Claims 17-20 and 23-26 rejected under 35 U.S.C. 103(a) as being unpatentable over Frankowsky in view of Miller in view of Shih in view of Tanishima et al (US Pat. 6,999,357; hereinafter referred to as Tabishima).

As per claims 17-19 and 23-25:

Frankowsky and Miller substantially teach the testing mode and method as detailed above. However, not explicitly disclosed is forcing usage of redundant elements which are not needed to be used for repairing the memory; and checking interaction between redundant elements.

However, Tanishima in an analogous art teaches forcing usage of redundant elements which are not needed to be used for repairing the memory; and faking defects to remap good elements with redundant elements (col. 6, lines 30-44 and col. 7, line 66 to col. 8, line 8). Therefore, it would have been obvious to a person of ordinary skill in the art at the time the invention was made to force usage of redundant elements which are not needed to be used for repairing the memory. This modification would have been obvious to one of ordinary skill in the art, at the time the invention was made, because one of ordinary skill in the art would have recognized that doing so would have enabled one to perform testing on the redundant memories without actual replacement with the redundant memory cell array (Tanishima; col. 8, lines 5-8).

Conclusion

Applicant's amendment necessitated the new ground(s) of rejection presented in this Office action. Accordingly, **THIS ACTION IS MADE FINAL**. See MPEP

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§ 706.07(a). Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to STEVE NGUYEN whose telephone number is (571)272-7214. The examiner can normally be reached on M-F, 10am-6:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kevin Ellis can be reached on (571) 272-4205. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

Steve Nguyen
Examiner
Art Unit 2117

/Kevin L Ellis/
Supervisory Patent Examiner, Art Unit 2117